

Application/Control No	0.	٥.
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09/839;370 Examiner

Hai<sub>.</sub>C. Pham

Applicant(s)/Patent	unde
Reexamination	

IIDA, MASARU Art Unit

2861

	SEAR	CHED	
Class	Subclass	Date	Examiner
347	237-238, 247	4/28/2006	HP
365	78	4/28/2006	HP
708	253	4/28/2006	HP
711	109	4/28/2006	HP

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST Text Search	4/28/2006	HP
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